Search Notes

	Application/Control No.	Applicant(s)/Patent under Reexamination
٠	09/843,573	DEMLER ET AL.
	Examiner	Art Unit
	Thomas H Stevens	2123

	SEARCHED				
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Goggle: Parallel Measurement; test-bened	5 24 05	THS
INSPEC: Inventor { Demler} test-bench; optimiser circuit	11	٠,
East: yarallel Simulation		
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